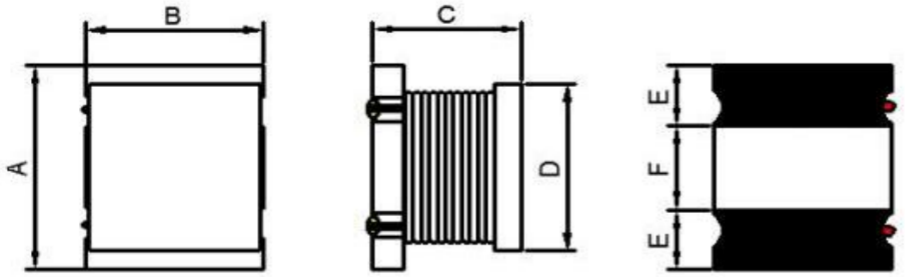
SMD Power Inductors

Dimensions(Unit:mm):



A	5.7±0.3
B	5.0±0.3
C	4.7±0.3
D	5.0±0.3
E	2.1±0.2
F	1.5±0.2

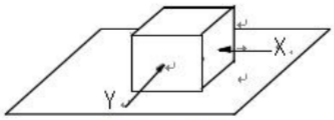
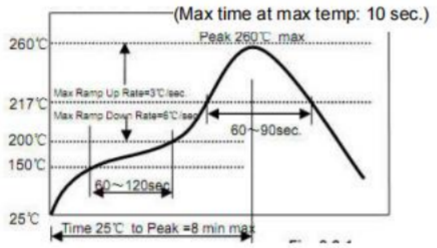
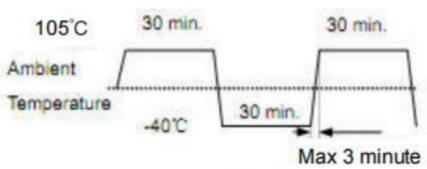
Electrical Chapacteristics:

Part No	Inductance 1MHz/0.25V	Tolerance	DCR ±40%	IDC MAX	S.R.F Min
Units	uH	±%	Ω	A	MHz
SCN5750NR27MST	0.27	20	0.01	5.3	300
SCN5750NR47MST	0.47	20	0.013	4.8	200
SCN5750N1R0MST	1.0	20	0.019	4.0	150
SCN5750N1R5MST	1.5	20	0.022	3.7	110
SCN5750N2R2MST	2.2	20	0.029	3.2	80
SCN5750N3R3MST	3.3	20	0.036	2.9	40
SCN5750N4R7MST	4.7	20	0.041	2.7	30
SCN5750N6R8MST	6.8	20	0.074	2.0	25
SCN5750N100MST	10.0	20	0.093	1.7	20
SCN5750N150MST	15.0	20	0.150	1.4	17
SCN5750N220MST	22.0	20	0.190	1.2	15
SCN5750N330MST	33.0	20	0.320	0.9	12
SCN5750N470MST	47.0	20	0.400	0.8	10
SCN5750N680MST	68.0	20	0.670	0.64	7.6
SCN5750N101MST	100	20	0.860	0.56	6.5
SCN5750N151MST	150	20	1.90	0.42	5.0
SCN5750N221MST	220	20	2.40	0.32	4.0
SCN5750N331MST	330	20	4.40	0.27	3.1

※1 : All test data is referenced to 25°C ambient;

※2 : This indicates the value of current when the inductance is 10% lower than its initial value at D.C superposition and D.C current when temperature rise ÄT=40℃.(Ta=25℃)

◆Rellability Test

Items	Requirements	Test Method/Condition
Terminal Strength	No removal or split of the termination or other defects shall occur  Fig.7.1-1	1.Solder the inductor to the testing jig (glass epoxy board shown in Fing.7.1-1) using eutectic solder. Then apply a force in the direction of the arrow. 2.10N force 3.Keep time: 5±2s
High Temperature	1.No visible mechanical damage 2.Inductance change: Within ±10%.	1.Storage Temperature :125±5℃ 2.Duration : 96 ±4 Hours 3.Recovery : then measured at room ambient temperature after placing 24 hours.
Low Temperature	1.No visible mechanical damage 2.Inductance change: Within ±10%	1.Temperature and time: -40±5℃ 2.Duration: 96 ±4 hours 3.Recovery : then measured at room ambient temperature after placing 24 hours
Vibration test	1.No visible mechanical damage 2.Inductance change: Within ±10%	1.Frequency range:10Hz~55Hz~10Hz 2.Amplitude:1.5mm p-p 3.Direction:X,Y,Z 4.Time:1 minute/cycle,2hours per axis
High Temperature Storage Tested	1.No visible mechanical damage. 2.Inductance change: Within ±10%	1.Storage Temperature :60±2℃ 2.Relative Humidity :90-95% RH 3.Duration : 96 ±4 Hours 4.Recovery : then measured at room ambient temperature after placing 24 hours
Resistance to Soldering Heat	1.No visible mechanical damage 2.Inductance change: Within ±10%  Fig.7.6-1	1.Re-flowing Profile: Please refer to Fig.7.6-1 2.Test board thickness: 1.0mm 3.Test board material: glass epoxy resin 4.The chip shall be stabilized at normal condition for 1~2 hours before measuring
Thermal Shock	1.No visible mechanical damage. 2.Inductance change: Within ±10%  Fig.7.7-1	1.Temperature and time: -40±3℃ for 30±3 min→ 105℃ for 30±3min, please refer to Fig.7.7-1 2.Transforming interval: Max,3 minute 3.Tested cycle: 100 cycles 4.The chip shall be stabilized at normal condition for 1~2 hours before measuring

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for Fixed Inductors ***category:***

Click to view products by Sunltech ***manufacturer:***

Other Similar products are found below :

CR32NP-100KC 70F224AI MHQ1005P10NJ MHQ1005P1N0S MHQ1005P2N4S MHQ1005P3N6S MHQ1005P5N1S MHQ1005P8N2J PE-53601NL PE-53602NL PG0936.113NLT 9220-20 9310-16 PM06-2N7 PM06-39NJ A01TK 1206CS-471XJ HC2-R47-R HC8-1R2-R HCF1305-3R3-R 1206CS-151XG RCH664NP-4R7M RCP1317NP-391L DH2280-4R7M DS1608C-106 B10TJ B82498B3101J000 ELJ-RE27NJF2 1812CS-153XJ 1812CS-183XJ 1812CS-223XJ 1812LS-104XJ 1812LS-105XJ 1812LS-124XJ 1812LS-154XJ 1812LS-223XJ 1812LS-224XJ 1812LS-563XJ 1812LS-683XJ 1812LS-824XJ NIN-FB101JTR110F NIN-FB471JTR62F NIN-FC1R5JTR220F NIN-HCR15JTRF NIN-HCR33JTRF NIN-HDR22JTRF NIN-HDR82JTRF NIN-HK2N7STRF NIN-PA150KTR370F NIN-PB100KTR550F